**Qualification Results Summary of REF43 Standard Space Level Change of Wafer Diameter and Fab Site**

|  |
| --- |
| **QUALIFICATION PLAN/STATUS** |
| **TEST** | **SPECIFICATION** | **SAMPLE SIZE** | **RESULTS** |
| Total Ionizing Dose RHA Level = 30, 50, & 100 K Rads (Si) | MIL-STD-883, Test Method 1019, Condition A(High Dose Rate) | 32 | 30K Rads – pass50 K Rads – pass100 K Rads – pass |
| High Temperature Operating Life Test | MIL-STD-883, Test Method 1015 | 45(0)Per wafer lot | In-process, Expected Completion Date November, 2015. |